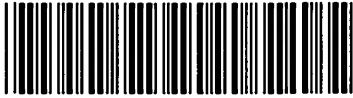


**Search Notes**

Application/Control No.

10/715,576

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

SASSER ET AL.

Art Unit

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**SEARCHED**

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| 385   | 88,92,76 | 3/22/2006 | JDS      |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|                                  | DATE      | EXMR |
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| See attached EAST search history | 3/22/2006 | JDS  |
| IEEE and INSPEC                  | 3/21/2006 | JDS  |
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